Form 1449 (Modified) Information Disclosure Statement By Applicant (Use Several Sheets if Necessary)	Atty. Docket No. EBRY0003 Applicant: Christopher M. Warnock, et al. Filing Date: November 28, 2003	Serial No.: 10/724,521 Group: 2624

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	3	6,389,541	5/1/2002	Patterson, Patrick E.			
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	1	2003/185448A1	10/2/2003	Dance, Christopher R., et al.				
	2	2004/0030680A1	2/1/2004	Veit, Daniel				
	3	2003/0037094A1	2/20/2003	Douceur et al.				

Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Assignee	Class	Sub-class	Translation Yes	No
	1	EP 0881591	12/2/1998	Stolin				
	2	EP 0881592	12/2/1998	Taylor				
	3	JP 2001175807	6/29/2001	Newman				

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	1	"Geometric Layout Analysis Techniques for Document Image Understanding," January 1998, Review, ITC-IRST Technical Report #9703-09, pp. 1-68, XP002229195, Trento, Italy.
	2	Bartal, "Probabilistic Approximation of Metric Spaces and Its Algorithmic Applications," 1996, In: FOCS Proceedings of the 37th Annual Symposium on Foundations of Computer Science. Washington DC, IEEE, Abstract, pp. 2-3, ISSN 0272-5428.
	3	Zhang, et al., "BIRCH: An Efficient Data Clustering Method for Very Large Databases," 1996, In: ACM Sigmod Record, Proceedings of the 1996 ACM SIGMOD International Conference on Management of Data, New York: ACM Press, Vol.25, Issue 2, pp. 103-14, ISSN 0163-5808.

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.